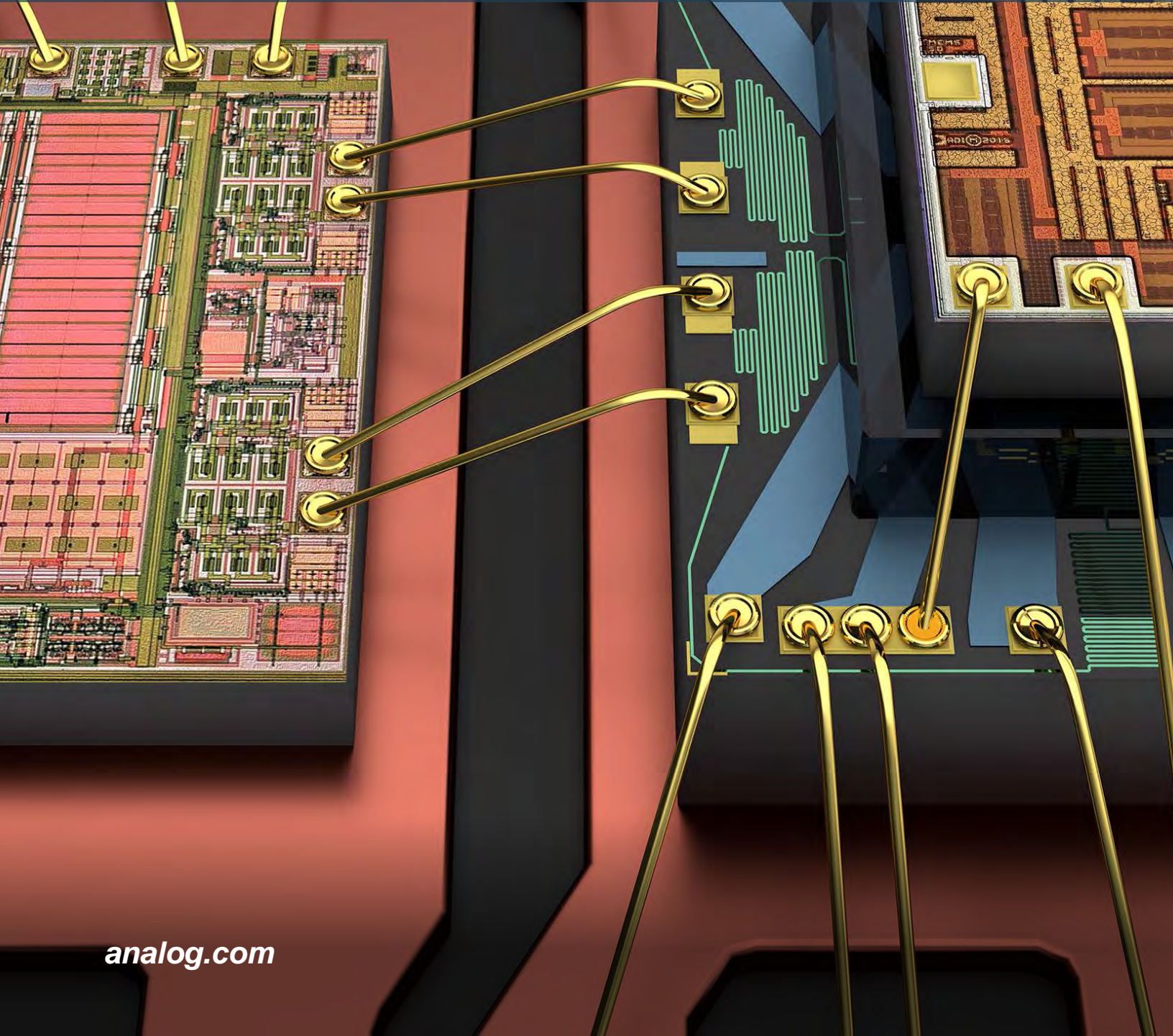


RELIABILITY REPORT



RELIABILITY DATA

LTC1992 LTC2053/54/55 LTC6240/41/42/44 LTC6800 LTC6910/11/12/15

6/1/2010

• **OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF FAILURES ⁽²⁾
SOIC/SOT/MSOP	847	0236	0908	1,136.92	0
SSOP/TSSOP	154	0421	0502	154.00	0
	1,001			1,290.92	0

• **PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	15,464	0212	0911	988.56	0
SSOP/TSSOP	243	0337	0726	74.93	0
QFN/DFN	500	0409	0807	27.63	0
	16,207			1,091.11	0

• **TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,508	0212	0911	1,043.17	0
SSOP/TSSOP	407	0337	0818	149.70	0
QFN/DFN	645	0409	0824	109.50	0
	3,560			1,302.37	0

• **THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	3,664	0213	0911	1,316.55	0
SSOP/TSSOP	159	0546	0726	79.50	0
QFN/DFN	396	0536	0733	39.60	0
	4,219			1,435.65	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 9.17 FITS

(3) Mean Time Between Failures in Years = 12,440

Note: 1 FIT = 1 Failure in One Billion Hours.